

Notice of References Cited	Application/Control No. 10/744,007	Applicant(s)/Patent Under Reexamination NAGANO ET AL.	
	Examiner Arlen Soderquist	Art Unit 1743	Page 1 of 3

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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	Examiner Arlen Soderquist	Art Unit 1743	Page 2 of 3

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Reexamination
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Examiner

Arlen Soderquist

Art Unit

1743

Page 3 of 3

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